

“Dose limited reliability of quantitative annular dark field scanning transmission electron microscopy for nano-particle atom-counting”. de Backer A, Martinez GT, MacArthur KE, Jones L, Béch   A, Nellist PD, Van Aert S, Ultramicroscopy **151**, 56 (2015). <http://doi.org/10.1016/j.ultramic.2014.11.028>